

AAEON Technology (Europe) B.V.

EP-SS25-256AACS 2.5" SATA SSD 256GB 3D TLC Specification

Version 1.1



Aaeon Technology (Europe) B.V.

Ekkersrijt 4090, 5692DA Son, The Netherlands

Tel: +31(0)499 745 200 E-mail: sales@aaeon.eu



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Revision History

| Revision | Draft Date | History | Author |
|----------|------------|---------------------------|-----------------------|
| 1.0 | 2018/08/01 | First release | Kai Liu |
| 1.1 | 2018/08/22 | Revision of the document. | Pascal van Buytene |



Product Overview

- Capacity
 - 256G

SATA Interface

- ■ SATA Revision 3.2
 - SATA 1.5Gbps, 3Gbps, and 6Gbps interface

Flash Interface

- ■ Flash Type: BiCS3 3D TLC
 - 2pcs to 8pcs of BGA132/152 flash

Performance

- Read: up to 560 MB/s
 - Write: up to 540 MB/s

${\bf Power\ Consumption}^{\rm Note1}$

- Active mode: < 3,210mW
 - Idle mode: < 220mW

- MTBF
 - 1.8 million
- Advanced Flash Management
 - Static and Dynamic Wear Leveling
 - Bad Block Management
 - TRIM
 - SMART
 - Over-Provision
 - Firmware Update
- Low Power Management
 - DIPM/HIPM/DEVSLP Mode
- Temperature Range
 - Operation: 0°C ~ 70°C
 - Storage: -40°C ~ 85°C
- RoHS compliant

Notes:

1. Please see "4.2 Power Consumption" for details.



Performance and Power Consumption

| | | | Performance | | | Power Consumption | | |
|------------------|------------------------------------|-------------------------|-----------------|---------------------------|-------------------------------|-------------------|---------------|--------------|
| | | CrystalDiskMark lometer | | | | | | |
| Capacity | Flash Structure | Read (MB/s) | Write (MB/s) | 4K Ran. Read (IOPS) | 4K Ran. Write (IOPS) | Read (mW) | Write (mW) | Idle (mW) |
| 256GB (240GB) | 64GB x 4, BGA132/152, BiCS3 TLC | 560 | 520 | 90,000 | 47,000 | 2,270 | 2,755 | 175 |

Notes:

- 1. Iometer test range is 8GB LBA with QD32.
- 2. Please see "4.2 Power Consumption" for details.
- 3. Power is based on IOMeter to measure



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1. INTRODUCTION

1.1. General Description

AAEON 2.5" SATA SSD delivers all the advantages of flash disk technology with Serial ATA I/II/III interface, including being fully compliant with standard 2.5-inch form factor, providing low power consumption compared to traditional hard drive and hot-swapping when removing/replacing/upgrading flash disks. The device is designed based on the standard 7-pin interface for data segment and 15-pin for power segment, as well as operating at a maximum operating frequency of 300MHz with 30MHz external crystal. Its capacity could provide a wide range up to 1TB. Moreover, it can reach up to 560MB/s read as well as 540MB/s write high performance based on Toshiba's BiCS3 3D Toggle TLC flash (with 1024MB DDR3 cache enabled and measured by CrystalDiskMark v5.0). Meanwhile, the power consumption of the 2.5" SSD is much lower than traditional hard drives.

1.2. Controller Block Diagram

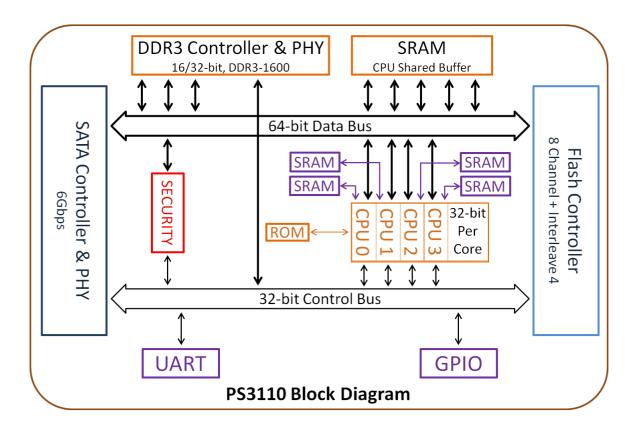


Figure 1-1 PS3110-S10 2.5" SATA SSD Controller Block Diagram



1.3. Product Block Diagram

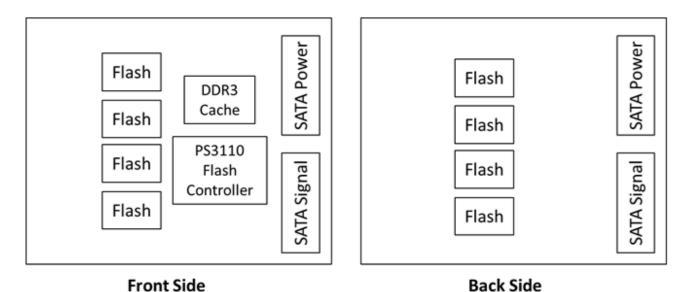


Figure 1-2 PS3110-S10 2.5" SATA SSD Product Block Diagram

1.4. Flash Management

1.4.1. Error Correction Code (ECC)

Flash memory cells will deteriorate with use, which might generate random bit errors in the stored data. Thus, PS3110-S10 SATA SSD applies the BCH ECC algorithm, which can detect and correct 120bits/2K Byte errors occur during read process, ensure data been read correctly, as well as protect data from corruption.

1.4.2. Wear Leveling

NAND flash devices can only undergo a limited number of program/erase cycles, and in most cases, the flash media are not used evenly. If some areas get updated more frequently than others, the lifetime of the device would be reduced significantly. Thus, Wear Leveling is applied to extend the lifespan of NAND Flash by evenly distributing write and erase cycles across the media.

AAEON provides advanced Wear Leveling algorithm, which can efficiently spread out the flash usage through the whole flash media area. Moreover, by implementing both dynamic and static Wear Leveling algorithms, the life expectancy of the NAND flash is greatly improved.



1.4.3. Bad Block Management

Bad blocks are blocks that include one or more invalid bits, and their reliability is not guaranteed. Blocks that are identified and marked as bad by the manufacturer are referred to as "Initial Bad Blocks". Bad blocks that are developed during the lifespan of the flash are named "Later Bad Blocks". AAEON implements an efficient bad block management algorithm to detect the factory-produced bad blocks and manages any bad blocks that appear with use. This practice further prevents data being stored into bad blocks and improves the data reliability.

1.4.4. TRIM

TRIM is a feature which helps improve the read/write performance and speed of solid-state drives (SSD). Unlike hard disk drives (HDD), SSDs are not able to overwrite existing data, so the available space gradually becomes smaller with each use. With the TRIM command, the operating system can inform the SSD which blocks of data are no longer in use and can be removed permanently. Thus, the SSD will perform the erase action, which prevents unused data from occupying blocks all the time.

1.4.5. SMART

SMART, an acronym for Self-Monitoring, Analysis and Reporting Technology, is an open standard that allows a disk drive to automatically detect its health and report potential failures. When a failure is recorded by SMART, users can choose to replace the drive to prevent unexpected outage or data loss. Moreover, SMART can inform users of impending failures while there is still time to perform proactive actions, such as copy data to another device.

1.4.6. Over-Provision

Over Provisioning refers to the inclusion of extra NAND capacity in a SSD, which is not accessible by users. With Over Provisioning, the performance and IOPS (Input/Output Operations per Second) are improved by providing the controller additional space to manage P/E cycles, which enhances the reliability and endurance as well. Moreover, the write amplification of the SSD becomes lower when the controller writes data to the flash.





1.4.7. Firmware Upgrade

Firmware can be considered as a set of instructions on how the device communicates with the host. Firmware will be upgradable when new features are added, compatibility issues are fixed, or read/write performance gets improved.

1.5. Low Power Management

1.5.1. DIPM/HIPM/DEVSLP Mode

SATA interfaces contain two low power management states for power saving: Partial and Slumber modes. For Partial mode, the device has to resume to full operation within 10 microseconds, whereas the device will spend 10 milliseconds to become fully operational in the Slumber mode. SATA interfaces allow low power modes to be initiated by Host (HIPM, Host Initiated Power Management) or Device (DIPM, Device Initiated Power Management). As for HIPM, Partial or Slumber mode can be invoked directly by the software. For DIPM, the device will send requests to enter Partial or Slumber mode.

And for the PS3110-S10 SSD, it can also support the DEVSLP mode for the power saving feature.

1.6. Power Loss Protection: Flushing Mechanism

Power Loss Protection is a mechanism to prevent data loss during unexpected power failure. DRAM is a volatile memory and frequently used as temporary cache or buffer between the controller and the NAND flash to improve the SSD performance. However, one major concern of the DRAM is that it is not able to keep data during power failure. Accordingly, the PS3110-S10 applies the *GuaranteedFlush* technology, which requests the controller to transfer data to the cache. For PS3110-S10, DDR performs as a cache, and its sizes include 512MB. Only when the data is fully committed to the NAND flash will the controller send acknowledgement (ACK) to the host. Such implementation can prevent false-positive performance and the risk of power cycling issues.

Additionally, it is critical for a controller to shorten the time the in-flight data stays in the cache. Thus, AAEON's PS3110-S10 applies an algorithm to reduce the amount of data resides in the cache to provide a better performance. This *SmartCacheFlush* technology allows incoming data to only have a "pit stop" in the cache and then move to the NAND flash at once. If the flash is jammed due to particular file sizes (such as random 4KB data), the cache will be treated as an "organizer", consolidating incoming data into groups before written into the flash to improve write amplification.

In sum, with Flush Mechanism, PS3110-S10 proves to provide the reliability required by consumer,





1.7.1. Secure Erase

Secure Erase is a standard ATA command and will write all "0x00" to fully wipe all the data on hard drives and SSDs. When this command is issued, the SSD controller will empty its storage blocks and return to its factory default settings.

1.7.2. Write Protect

When a SSD contains too many bad blocks and data are continuously written in, then the SSD might not be usable anymore. Thus, Write Protect is a mechanism to prevent data from being written in and protect the accuracy of data that are already stored in the SSD.

1.8. SSD Lifetime Management

1.8.1. Thermal Monitor (Optional)

Thermal monitors are devices for measuring temperature and can be found in SSDs in order to issue warnings when SSDs go beyond a certain temperature. The higher temperature the thermal monitor detects, the more power the SSD consumes, causing the SSD to get aging quickly. Hence, the processing speed of a SSD should be under control to prevent temperature from exceeding a certain range. Meanwhile, the SSD can achieve power savings.

1.9. An Adaptive Approach to Performance Tuning

1.9.1. Throughput

Based on the available space of the disk, PS3110-S10 will regulate the read/write speed and manage the performance of throughput. When there still remains a lot of space, the firmware will continuously perform read/write action. There is still no need to implement garbage collection to allocate and release memory, which will accelerate the read/write processing to improve the performance. Contrarily, when the space is going to be used up, PS3110-S10 will slow down the read/write processing and implement garbage collection to release memory. Hence, read/write performance will become slower.



1.9.2. Predict & Fetch

Normally, when the Host tries to read data from the SSD, the SSD will only perform one read action after receiving one command. However, PS3110-S10 applies *Predict & Fetch* to improve the read speed. When the host issues sequential read commands to the SSD, the SSD will automatically expect that the following will also be read commands. Thus, before receiving the next command, flash has already prepared the data. Accordingly, this accelerates the data processing time, and the host does not need to wait so long to receive data.



2. PRODUCT SPECIFICATIONS

- Capacity
 - Supported capacity^{Note1}: 256GB (support 48-bit addressing mode)
- Electrical/Physical Interface
- SATA Interface
 - ◆ Compliant with SATA Revision 3.2
 - Compatible with SATA 1.5Gbps, 3Gbps and 6Gbps interface
 - ◆ NCQ support up to queue depth = 32
 - Support power management
 - ◆ Support expanded register for SATA protocol 48 bits addressing mode
 - Embedded BIST function for SATA PHY for low cost mass production

Supported NAND Flash

- Toshiba BiCS3 3D TLC
- Contain up to 8pcs of BGA flash
- ECC Scheme
 - PS3110-S10 2.5" SSD can correct up to 120 bits error in 2K Byte data.
- UART function
- GPIO
- Support SMART and TRIM commands
- Support Log Drive Feature



Performance

| | | Performance | | | |
|----------|-----------------------|--------------------|-------|---------|---------|
| | | CrystalDiskMark | | lometer | |
| Capacity | Flash Structure | Read | Write | 4K Ran. | 4K Ran. |
| | | (MB/s) (MB/s) Read | Read | Write | |
| | | | | (IOPS) | (IOPS) |
| 256GB | 64GB x 4, BGA132/152, | 560 | 520 | 90,000 | 47,000 |
| (240GB) | BiCS3 TLC | 300 | 320 | 30,000 | 47,000 |

- 1. The performance was measured using CrystalDiskMark with SATA 6Gbps host.
- 2. Iometer test range is 8GB LBA with QD32.
- 3. Samples were built using Toshiba BiCS3 3D Toggle TLC NAND flash
- 4. Performance may differ according to flash configuration and platform
- 5. The table above is for reference only. The criteria for MP (mass production) and for accepting goods shall be discussed based on different flash configuration



3. ENVIRONMENTAL SPECIFICATIONS

3.1. Environmental Conditions

3.1.1. Temperature and Humidity

Temperature:

Storage: -40°C to 85°COperational: 0°C to 70°C

Humidity: RH 90% under 40°C (operational)

Table 3-1 High Temperature Test Condition

| | Temperature | Humidity | Test Time |
|-----------|-------------|----------|-----------|
| Operation | 70°C | 0% RH | 72 hours |
| Storage | 85°C | 0% RH | 72 hours |

Result: No any abnormality is detected.

Table 3-2 Low Temperature Test Condition

| | Temperature | Humidity | Test Time |
|-----------|-------------|----------|-----------|
| Operation | 0°C | 0% RH | 72 hours |
| Storage | -40°C | 0% RH | 72 hours |

Result: No any abnormality is detected.

Table 3-3 High Humidity Test Condition

| | Temperature | Humidity | Test Time |
|-----------|-------------|----------|-----------|
| Operation | 40°C | 90% RH | 4 hours |
| Storage | 40°C | 93% RH | 72 hours |

Result: No any abnormality is detected.

Table 3-4 Temperature Cycle Test

| | Tomporatura | Test Time | Cyclo |
|-----------|-------------|-----------|-----------|
| | Temperature | rest rime | Cycle |
| Operation | 0°C | 30 min | 10 Cycles |
| | 70°C | 30 min | 10 Cycles |
| Storage | -40°C | 30 min | 10 Cycles |
| | 85°C | 30 min | 10 Cycles |

Result: No any abnormality is detected.



3.1.2.Shock

Table 3-5 PS3110-S10 2.5" SATA SSD Shock Specification

| | Acceleration Force | Half Sin Pulse Duration |
|-----------------|--------------------|-------------------------|
| Non-operational | 1500G | 0.5ms |

Result: No any abnormality is detected when power on.

3.1.3. Vibration

Table 3-6 PS3110-S10 2.5" SATA SSD Vibration Specification

| | Vibration Orientation | | |
|---|-----------------------|-----------------------|------------------------------|
| Frequency/Displacement Frequency/Acceleration | | Vibration Officiation | |
| Non-operational | 20Hz~80Hz/1.52mm | 80Hz~2000Hz/20G | X, Y, Z axis/30 min for each |

Result: No any abnormality is detected when power on.

3.1.4. Drop

Table 3-7 PS3110-S10 2.5" SATA SSD Drop Specification

| | Height of Drop | Number of Drop |
|-----------------|----------------|---------------------|
| Non-operational | 80cm free fall | 6 face of each unit |

Result: No any abnormality is detected when power on.

3.1.5. Bending

Table 3-8 PS3110-S10 2.5" SATA SSD Bending Specification

| | Force | Action |
|-----------------|-------|------------------|
| Non-operational | ≥ 10N | Hold 1min/5times |

Result: No any abnormality is detected when power on.

3.1.6.Torque

Table 3-9 PS3110-S10 2.5" SATA SSD Torque Specification

| | Force | Action |
|-----------------|-----------------|------------------|
| Non-operational | 0.5N-m or 5 deg | Hold 5min/5times |

Result: No any abnormality is detected when power on.



3.1.7. EMI Compliance

FCC: CISPR22CE: EN55022

BSMI: 13438

3.2. MTBF

• 2.5" SSD up to 1.8 Millions.

NOTES:

MTBF value is simulation based on the actual FIT rate report form component suppliers.

3.3. Certification & Compliance

- RoHS
- Halogen Free
- SATA III (SATA Rev. 3.2)
- Up to ATA/ATAPI-8 (Including S.M.A.R.T)
- WHCK



4. ELECTRICAL SPECIFICATIONS

4.1. Supply Voltage

Table 4-1 Supply Voltage of PS3110-S10 2.5" SATA SSD

| Parameter | Rating |
|-------------------|----------------|
| Operating Voltage | 5V+/-5% |
| Maximum Ripple | 100mV, 0~30MHz |

4.2. Power Consumption

Table 4-2 Power Consumption of PS3110-S10 2.5" SATA SSD

| Capacity | Flash Structure | Flash Type | Read | Write | Partial | Slumber | Idle |
|----------|--------------------|----------------|-------|-------|---------|---------|------|
| 256GB | 64GB x 4 | BGA, BiCS3 TLC | 2,270 | 2,755 | 70 | 70 | 175 |
| (240GB) | 04GB X 4 | BGA, BICSS TEC | 2,270 | 2,755 | 70 | 70 | 1/5 |

Unit: mW

NOTES:

- 1. The average value of power consumption is achieved based on 100% conversion efficiency.
- 2. The measured power voltage is 5V.
- 3. Samples were built of Toshiba BiCS3 3D Toggle TLC NAND flash and measured under ambient temperature.
- 4. Sequential R/W is measured while testing 1MB sequential R/W 3 times by IOMeter.
- 5. Power Consumption may differ according to flash configuration and platform.



5.1. Pin Assignment and Descriptions

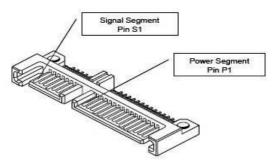


Figure 5-1 PS3110-S10 2.5" SATA SSD Pin Assignment

Table 5-1 Signal Segment Pin Assignment and Descriptions

| Pin Number | Function |
|------------|----------------------------------|
| S1 | GND |
| S2 | A+ (Differential Signal Pair A) |
| \$3 | A – (Differential Signal Pair A) |
| S4 | GND |
| S5 | B – (Differential Signal Pair B) |
| \$6 | B+ (Differential Signal Pair B) |
| S7 | GND |

Table 5-2 Power Segment Pin Assignment and Descriptions

| Pin Number | Function | | |
|------------|---------------------------|--|--|
| P1 | Not Used (3.3V) | | |
| P2 | Not Used (3.3V) | | |
| Р3 | DEVSLP | | |
| P4 | GND | | |
| P5 | GND | | |
| P6 | GND | | |
| P7 | 5V pre-charge | | |
| P8 | 5V | | |
| Р9 | 5V | | |
| P10 | GND | | |
| P11 | Reserved | | |
| P12 | GND | | |
| P13 | Not Used (12V pre-charge) | | |
| P14 | Not Used (12V) | | |
| P15 | Not Used (12V) | | |



6. SUPPORTED COMMANDS

6.1. ATA Command List

Table 6-1 ATA Command List

| Op-Code | Command Description | (| Op-Code | Command Description |
|---------|-----------------------------------|-----|----------|---|
| 00h | NOP | 60h | | Read FPDMA Queued |
| 06h | Data Set Management | 61h | | Write FPDMA Queued |
| 10h | Recalibrate | 70h | | Seek |
| 20h | Read Sectors | 90h | | Execute Device Diagnostic |
| 21h | Read Sectors without Retry | 91h | | Initialize Device Parameters |
| 24h | Read Sectors EXT | 92h | | Download Microcode |
| 25h | Read DMA EXT | 93h | | Download Microcode DMA |
| 27h | Read Native Max Address EXT | B0h | | SMART |
| 29h | Read Multiple EXT | B0h | D0h | SMART READ DATA |
| 2Fh | Read Log EXT | B0h | D1h | SMART READ DATA ATTRIBUTE THRESHOLD |
| 30h | Write Sectors | B0h | D2h | SMART ENABLE/DISABLE ATTRIBUTE AUTOSAVE |
| 31h | Write Sectors without Retry | B0h | D3h | SMART SAVE ATTRIBUTE VALUES |
| 34h | Write Sectors EXT | B0h | D4h | SMART EXECUTE OFF-LINE IMMEDIATE |
| 35h | Write DMA EXT | B0h | D5h | SMART READ LOG |
| 37h | Set Native Max Address EXT | B0h | D6h | SMART WRITE LOG |
| 39h | Write Multiple EXT | B0h | D8h | SMART ENABLE OPERATIONS |
| 3Dh | Write DMA FUA EXT | B0h | D9h | SMART DISABLE OPERATIONS |
| 3Fh | Write Long EXT | B0h | DAh | SMART RETURN STATUS |
| 40h | Read Verify Sectors | B0h | DBh | SMART ENABLE/DISABLE AUTOMATIC OFF-LINE |
| 41h | Read Verify Sectors without Retry | B1h | <u> </u> | DEVICE CONFIGURATION OVERLAY |
| 42h | Read Verify Sectors EXT | B1h | C0h | DEVICE CONFIGURATION RESTORE |
| 45h | Write Uncorrectable EXT | B1h | C1h | DEVICE CONFIGURATION FREEZE LOCK |
| 47h | Read Log DMA EXT | B1h | C2h | DEVICE CONFIGURATION IDENTIFY |
| | | | | |



| (| Op-Code | Command Description | (| Op-Co | de | Command Description | |
|-----|---------|-----------------------------------|-----|------------------------------|-----|---|--|
| B1h | C4h | DEVICE CONFIGURATION IDENTIFY DMA | ECh | | | Identify Device | |
| B1h | C5h | DEVICE CONFIGURATION SET DMA | EFh | | | Set Features | |
| C4h | • | Read Multiple | EFh | 02h | | Enable 8-bit PIO transfer mode | |
| C5h | | Write Multiple | EFh | 03h | | Set transfer mode based on value in Count field | |
| C6h | | Set Multiple Mode | EFh | 05h | | Enable advanced power management | |
| C8h | | Read DMA | EFh | 10h | | Enable use of Serial ATA feature | |
| C9h | | Read DMA without Retry | EFh | 10h | 02h | Enable DMA Setup FIS Auto-Activate optimization | |
| CAh | | Write DMA | EFh | 10h | 03h | Enable Device-initiated interface power state (DIPM) | |
| CBh | | Write DMA without Retry | EFh | 10h | 06h | Enable Software Settings Preservation (SSP) | |
| CEh | | Write Multiple FUA EXT | EFh | 10h | 07h | Enable Device Automatic Partial to Slumber transitions | |
| E0h | | Standby Immediate | EFh | 10h | 09h | Enable Device Sleep | |
| E1h | | Idle Immediate | EFh | 55h | | Disable read look-ahead feature | |
| E2h | | Standby | EFh | 66h | | Disable reverting to power-on defaults | |
| E3h | | Idle | EFh | 82h | | Disable write cache | |
| E4h | | Read Buffer | EFh | 85h | | Disable advanced power management | |
| E5h | | Check Power Mode | EFh | 90h | | Disable use of Serial ATA feature set | |
| E6h | | Sleep | EFh | 90h | 02h | Disable DMA Setup FIS Auto-Activate optimization | |
| E7h | | Flush Cache | EFh | 90h | 03h | Disable Device-initiated interface power state (DIPM) | |
| E8h | | Write Buffer | EFh | 90h | 06h | Disable Software Settings Preservation (SSP) | |
| E9h | | Read Buffer DMA | EFh | 90h | 07h | Disable Device Automatic Partial to Slumber transitions | |
| EAh | | Flush Cache EXT | EFh | 90h 09h Disable Device Sleep | | Disable Device Sleep | |
| EBh | | Write Buffer DMA | EFh | AAh | | Enable read look-ahead feature | |



| Op-Code Command Description Op-Code Command | | Command Description | | |
|---|---|---------------------------------------|---------------------------|----------------------|
| EFh | CCh | Enable reverting to power-on defaults | F4h | Security Erase Unit |
| F1h | | Security Set Password | F5h | Security Freeze Lock |
| F2h | F2h Security Unlock F6h Security Disable Password | | Security Disable Password | |
| F3h Security Erase Prepare | | F8h | Read Native Max Address | |



6.2. Identify Device Data

The following table details the sector data returned by the IDENTIFY DEVICE command.

Table 6-2 List of Device Identification

| Word | ATA Identify Parameter | Value |
|-------|--|-----------|
| 0 | General configuration | 0040h |
| 1 | Number of cylinders in the default CHS translation | 3FFFh |
| 2 | Specific configuration | C837h |
| 3 | Number of heads in the default CHS translation | 0010h |
| 4-5 | Retired | 0000h |
| 6 | Number of sectors per track in the default CHS translation | 003Fh |
| 7-8 | Reserved for the CFA | 0000h |
| 9 | Obsolete | 0000h |
| 10-19 | Serial number | ASCII |
| 20 | Retired | 0000h |
| 21 | Retired | 0000h |
| 22 | Obsolete | 0000h |
| 23-26 | Firmware revision | ASCII |
| 27-46 | Model number | ASCII |
| 47 | READ/WRITE MULTIPLE commands function | 8010h |
| 48 | Trusted Computing feature set options | 4000h |
| 49 | Capabilities | 2F00h |
| 50 | Capabilities | 4000h |
| 51-52 | Obsolete | 0000h |
| 53 | field validity | 0007h |
| 54 | Number of cylinders in the current CHS translation | 3FFFh |
| 55 | Number of heads in the current CHS translation | 0010h |
| 56 | Number of sectors per track in the current CHS translation | 003Fh |
| 57-58 | Current capacity in sectors | 00FBFC10h |
| 59 | Multiple sector setting | 9D10h |
| 60-61 | Total number of user addressable logical sectors for 28-bit commands | *3 |
| 62 | Obsolete | 0000h |
| 63 | Multiword DMA modes | 0407h |
| 64 | PIO mode supported | 0003h |
| 65 | Minimum Multiword DMA transfer cycle time per word | 0078h |
| 66 | Manufacturer's recommended Multiword DMA transfer cycle time | 0078h |



| Word | ATA Identify Parameter | Value |
|---------|--|-------------|
| 67 | Minimum PIO transfer cycle time without flow control | 0078h |
| 68 | Minimum PIO transfer cycle time with IORDY flow control | 0078h |
| 69 | Additional Supported | 5F20h |
| 70-73 | Reserved | 0000h |
| 74 | Reserved | 0000h |
| 75 | Queue depth | 001Fh |
| 76 | Serial ATA Capabilities | E70Eh |
| 77 | Supported Serial ATA Phy speed | 86h/84h/82h |
| 78 | Serial ATA features supported | 054Ch |
| 79 | Serial ATA features enabled | 0040h |
| 80 | Major version number | 03F8h |
| 81 | Minor version number | 0000h |
| 82 | Commands and feature sets supported | 746Bh |
| 83 | Commands and feature sets supported | 7D09h |
| 84 | Commands and feature sets supported | 4163h |
| 85 | Commands and feature sets supported or enabled | 7469h |
| 86 | Commands and feature sets supported or enabled | BC09h |
| 87 | Commands and feature sets supported or enabled | 4163h |
| 88 | Ultra DMA modes | 007Fh |
| 89 | Time required for Normal Erase mode SECURITY ERASE UNIT command | 0001h |
| 90 | Time required for an Enhanced Erase mode SECURITY ERASE UNIT command | 0001h |
| 91 | Current APM level value | 00FEh |
| 92 | Master Password Identifier | FFFEh |
| 93 | Hardware reset result | 0000h |
| 94 | Current AAM value | 0000h |
| 95 | Stream Minimum Request Size | 0000h |
| 96 | Streaming Transfer Time - DMA | 0000h |
| 97 | Streaming Access Latency -DMA and PIO | 0000h |
| 98-99 | Streaming Performance Granularity | 0000h |
| 100-103 | Total Number of User Addressable Logical Sectors for 48-bit commands | *4 |
| 104 | Streaming Transfer Time - PIO | 0000h |
| 105 | Maximum number of 512-byte blocks of LBA Range Entries per DATA SET MANAGEMENT command | 0008h |



| Word | ATA Identify Parameter | Value |
|-----------|--|-----------------|
| 106 | Physical sector size / logical sector size | 4000h |
| 107 I | nter-seek delay for ISO 7999 standard acoustic testing | 0000h |
| 108-111 | Norld wide name | Vender Specific |
| 112-115 F | Reserved | 0000h |
| 116 | Reserved for TLC | 0000h |
| 117-118 l | ogical sector size | 0000h |
| 119 | Commands and feature sets supported | 401Dh |
| 120 | Commands and feature sets supported or enabled | 401Dh |
| 121-124 F | Reserved for expanded supported and enabled settings | 0000h |
| 125-126 F | Reserved for expanded supported and enabled settings | 0000h |
| 127 | 127 Obsolete | |
| 128 | Security status | 0021h |
| 129-159 | /endor specific | 0000h |
| 160 | CFA power mode | 0000h |
| 161-164 F | Reserved for the CFA | 0000h |
| 165-167 F | Reserved for the CFA | 0000h |
| 168 | Device Nominal Form Factor | 0003h |
| 169 [| DATA SET MANAGEMENT is supported | 0001h |
| 170-173 | Additional Product Identifier | 0000h |
| 174-175 F | Reserved | 0000h |
| 176-205 | Current media serial number | 0000h |
| 206 | SCT Command Transport | 0000h |
| 207-208 F | Reserved for CE-ATA | 0000h |
| 209 | Alignment of logical blocks within a physical block | 4000h |
| 210-211 | Write-Read-Verify Sector Count Mode 3 | 0000h |
| 212-213 | Write-Read-Verify Sector Count Mode 2 | 0000h |
| 214 | NV Cache Capabilities | 0000h |
| 215-216 | NV Cache Size in Logical Blocks | 0000h |
| 217 | Nominal media rotation rate | 0001h |
| 218 | Reserved | 0000h |
| 219 | NV Cache Options | 0000h |
| 220 (| Current mode of the Write-Read-Verify feature set | 0000h |
| 221 | Reserved | 0000h |
| 222 | Fransport major version number | 107Fh |
| 223 | Fransport minor version number | 0000h |
| | · | |
| 224-227 | Reversed for CE-ATA | 0000h |



| Word | ATA Identify Parameter | Value |
|---------|---|-------|
| 230-233 | Extend Number of User Addressable Sectors | 0000h |
| 234 | Minimum number of 512-byte data blocks per DOWNLOAD MICROCODE command for mode 03h | 0001h |
| 235 | Maximum number of 512-byte data blocks per DOWNLOAD MICROCODE command for mode 03h | FFFFh |
| 236-239 | Reserved | 0000h |
| 240-242 | Reserved | 0000h |
| 243 | Reserved | 0000h |
| 244-247 | Reserved | 0000h |
| 248-251 | Reserved | 0000h |
| 252-254 | Reserved | 0000h |
| 255 | Integrity word | xxA5h |

Table 6-3 List of Device Identification for 256G Capacity

| Capacity | *1 | *2 | *3 | *4 |
|----------|------------------|----------------|----------------|------------------|
| (GB) | (Word 1/Word 54) | (Word 57 – 58) | (Word 60 – 61) | (Word 100 – 103) |
| 256 | 3FFFh | FBFC10h | FFFFFFFh | 1DCF32B0 |



7. PHYSICAL DIMENSION

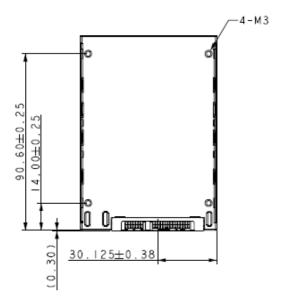
❖ 100.00mm (L) x 69.85mm (W) x 7.00mm (H)

PCB PN: A069010ME008401N

Connector Material : Au

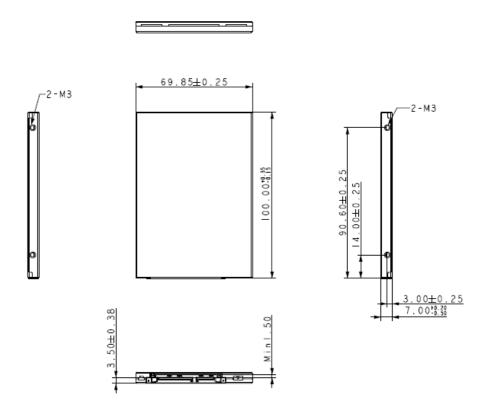


Bottom View

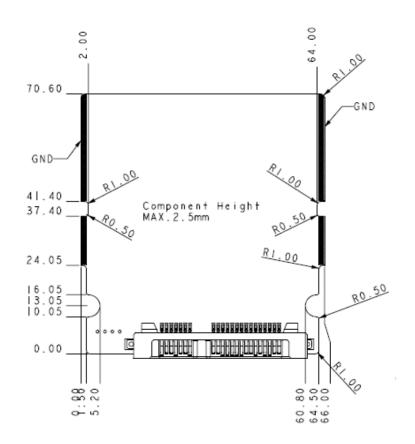


Top View/Side View



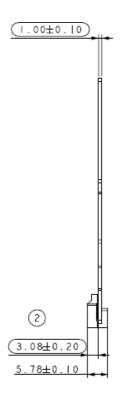


PCB Drawing: A069010ME008401N (BGA x 8pcs)

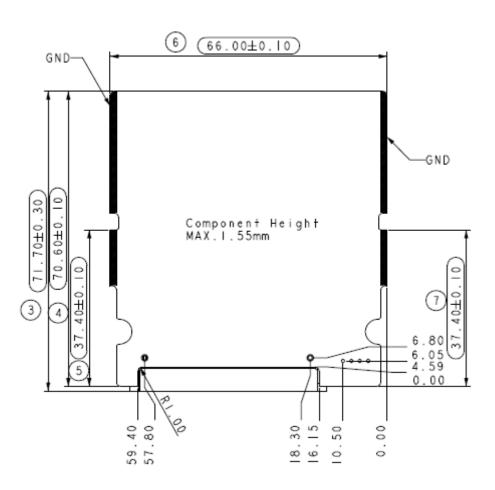


Top View





Side View



Bottom View



8. REFERENCES

The following table is to list out the standards that have been adopted for designing the product.

Table 9-1 List of References

| Title | Acronym/Source |
|-------------------------|---|
| RoHS | Restriction of Hazardous Substances Directive; for further information, |
| КОПЗ | please contact us as info@aaeon.eu . |
| Serial ATA Revision 3.2 | http://www.sata-io.org |
| ATA-8 spec | http://www.t13.org |

9. TERMINOLOGY

The following table is to list out the acronyms that have been applied throughout the document.

Table 10-1 List of Terminology

| Term | Definitions |
|------------|--|
| ATTO | Commercial performance benchmark application |
| DDR | Double data rate (SDRAM) |
| DIPM | Device initiated power management |
| HIPM | Host initiated power management |
| LBA | Logical block addressing |
| MB | Mega-byte |
| MTBF | Mean time between failures |
| NCQ | Native command queue |
| SATA | Serial advanced technology attachment |
| S.M.A.R.T. | Self-monitoring, analysis and reporting technology |
| SSD | Solid state disk |

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